


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565297	<b>Applicant(s)/Patent Under Reexamination</b> ONOYAMA ET AL.
	<b>Examiner</b> ame asssigneeFrederick J Parker	<b>Art Unit</b> 1792

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search, strategy within, incl. inventors	11-25-08	fjp
Reviewed similar case/same asssignee sn 10/546807 for DP & PA	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
427	interference search	11-25-8	"
524	"	11-25-08	"

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